Raman scattering at terahertz frequencies enabled by an infrared free electron laser

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Long-wavelength (THz) Raman scattering





THz Raman scattering: Challenges

- > scattering efficiency, λ^{-4}
- > either free carrier absorption, λ^2
- or excitation avoiding free electrons ?
- > under optical phonon excitation
- = high orders of electron-phonon interaction
- > technical (filters, collecting optics)
- = no commercial THz components
 - (notch or low pass filter, lens objective)



Interactions resulting in the Raman light scattering



Interactions resulting in the Raman light scattering



electron-phonon interactions

lattice anharmonicities

nanotherm.es/images/phonon2.png

hv

Interaction orders (N-phonon(s) scattering)



(Phys Lett 44A, 517 (1973))



Key notes:

enabling THz Raman scattering in doped silicon

features of THz Raman scattering in doped silicon



THz intracenter Raman lasing from a doped Si.



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Experimental

Float-zone grown

^{nat}Si: P, Sb, As, Bi

²⁸Si: P, Bi

^{nat}Si: Sb+P,

 $N_D \sim (2-14) \times 10^{15} \text{ cm}^{-3}$





resonator on total internal reflection



IR free electron laser

(FELIX, NL) 5-10 ps pulses 1/20/40 ns separation up to 1 MW peak λ ~16-42 µm

(CLIO, F) 5-10 ps pulses 16 ns separation up to 10 MW peak λ ~16-42 µm

(FELBE, D) 5-10 ps pulses 77 ns separation up to 0.1 MW peak λ ~16-22 µm



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Volume enhanced ?

Transparent in THz

band-gap laser up to ~1e14 centers up to ~1e10 centers under band-gap

up to ~1e14 centers



resonator on total internal reflection





Volume enhanced !

532 nm band-gap laser *skin depth 1 μm*

electronic Raman in Si 785 nm almost BG skin depth 10 μm e-Raman in Si:Bi (40.8meV=30μm) 1064 nm below BG skin depth 1 mm e-Raman in n-Si (~23meV=54µm)











intra- and inter-valley phonons (a multi-valley semiconductor)

- Zone-centered optical phonons $f_{LTO}(\Gamma) \approx 15.6 \text{ THz}$
- Phonons related to the critical points of the Brillouin zone ٠
- Intervalley phonons, 3-15 THz



[001]

g

[010]

0.855×K⁰¹⁰



Electronic resonant Raman scattering

$$P(\omega_{\rm S}) \sim \left| \frac{\langle v|H_{\rm e-L}|{\rm GS} \rangle \times \langle v|H_{\rm e-S}|{\rm ES} \rangle \times \langle {\rm ES}|H_{\rm e-ph}|{\rm GS} \rangle}{[\hbar\omega_{\rm PUMP} - \Delta E_{\rm V}] \times [\hbar\omega_{\rm PUMP} - \hbar\omega_{\rm S} - \Delta E_{\rm ES}]} \right|^{2}$$
$$\Delta E_{\rm V} = (E_{\rm GS} - E_{\rm v} + ih\Gamma_{\rm S})$$
$$\Delta E_{\rm ES} = (E_{\rm GS} - E_{\rm ES})$$
$$10$$

resonance to an impurity Raman-active transition: outgoing

$$\hbar \omega_{\text{PUMP}} - \hbar \omega_{\text{S}} = \Delta E_{\text{ES}}$$

1s(E) \rightarrow 1s(A₁) Raman-active

resonance in pumping: ingoing $\hbar\omega_{\rm PUMP} = E_{\rm GS} - E_{\rm v}$



0



photon-bound_electron-phonon (free_electron-free) interaction





THz Raman scattering: Overcoming the Challenges



Raman scattering at THz frequencies:

 enabling 7-17 THz Raman scattering in n-silicon:
 resonant to donor electronic states coupled by intervalley phonons
 + large number of scattering centers (volume, up to ~1e14 centers)
 + free_electron-free (photon-bound_electron-phonon) interaction cancels free carrier absorption

◆ features of the stimulated THz Raman scattering in n-silicon

+ lasing threshold exceed 3e23 photons/cm²/s, the lowest ones are for the Si:Sb and Si:Bi with the particular donor-phonon resonances
+ the Stokes shifts (2.5 - 9 THz) of the Raman lasing corresponds to a Raman-active donor 1s(A₁)-1s(E) transition

- + the Raman gain is estimated to be up to 5.8 cm/MW
- + the optical conversion factor is within 1e-8 1e-9

+ the donor concentration limit < 8e15/cm³ (1s(A₁)-1s(E) donor transition broadening)



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